

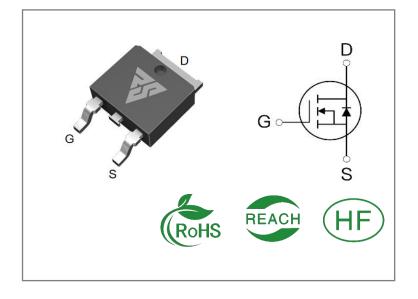
ID	R _{DS} (ON)(Typ)	VDSS
7.3A	530mΩ	700V

Applications:

- Switch Mode Power Supply(SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)
- AC-DC Switching Power Supply

Features:

- Fast switching speed
- 100% avalanche tested
- Improved dv/dt capability



Ordering Information

Part Number	Package	Package Marking		Qty.	
RS70R600D	T0-252	RS70R600D	Tape&reel	2500 PCS	

Absolute Maximun Ratings Tc= 25℃ unless otherwise specified

Symbol	Parameter	RS70R600D	Units		
VDSS	Drain-to-Source Voltage	700	V		
ID	Continuous Drain Current TC=25℃	7.3			
ID	Continuous Drain Current TC=100°C	4.5	А		
IDM	Pulsed Drain Current (Note*1)	24			
PD	Power Dissipation	60	W		
VGS	VGS Gate- to- Source Voltage		V		
EAS	Single Pulse Avalanche Engergy L=10mH,VDS= 50V, RG = 25 Ω , TC=25 $^{\circ}$ C	129	mJ		
dv/dt	MOSFET dv/ dt ruggedness VDS = 0400V	50	V/ns		
dv/dt	Reverse diode dv/dt VDS = 0400V, Tj = 25°C, ISD≤ID	15	V/ns		
	Maximum Temperature for Soldering	300			
TL TPKG	Leads at 0.063in(1.6mm)from Case for 10 seconds Package Body for 10 seconds	260	$^{\circ}$		
TJ and TSTG	Operating Junction and Storage Temperature Range	-55 to 150			

^{*} Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the" Absolute Maximum Ratings" Table may cause permanent damage to the device.



Thermal Resistance

Symbol	Parameter	RS70R600D	Units	Test Conditions
				Drain lead soldered to water cooled
RθJC	Junction-to-Case	2.1		heatsink, PD adjusted for a peak
			°C/W	junction temperature of + 1 5 0 $^{\circ}$ C
RθJA	Junction-to- Ambient	62.5		1 cubic foot chamber,free air.

OFF Characteristics TJ= 25 °C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
D)/DCC	Drain- to- source Breakdown	700			\/	VGS=0V
BVDSS	Voltage				V	ID=250μA
IDSS	Drain- to- Source Leakage Current			1		VDS=700V
					μΑ	VGS=0V
	Gate- to- Source Forward Leakage			100	- nA	VGS=30V
IGSS						VDS=0V
				-100		VGS=-30V
	Gate- to- Source Reverse Leakage					VDS=0V

ON Characteristics TJ=25 °C unless otherwise specified

Symbol	Parameter		Тур.	Max.	Units	Test Conditions
RDS(on)	Static Drain- to- Source On-		530	600	mΩ	VGS=10V
KD3(0H)	Resistance(Note*2)		330	800	11122	ID=2A
VGS(TH)	Cata Thuashald Valtage	2		4	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	VGS=VDS
	Gate Threshold Voltage				V	ID=250μA

Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter		Тур.	Max.	Units	Test Conditions
td(ON)	Turn- on Delay Time		17			
trise	Rise Time		26			VDS=350V
td(OFF)	Turn- OFF Delay Time		53		nS	ID=7.3A RG=25Ω
tfall	Fall Time		38			



Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
Ciss	Input Capacitance		473			VGS=0V
Coss	Output Capacitance		36		pF	VDS=50V
Crss	Reverse Transfer Capacitance		1.7			f=400kHz
Qg	Total Gate Charge		13			VDS=520V
Qgs	Gate- to- Source Charge		2.1		nC	ID=7.3A
Qgd	Gate-to-Drain(" Miller") Charge		6.9			VGS=10V

Source-Drain Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions	
IS	Continuous Source Current			7.3	Α	Integral pn- diode	
ISM	Maximum Pulsed Current			24	Α	in MOSFET	
VSD	Diode Forward Voltage			1.2	٧	IS=7.3A,VGS=0V	
trr	Reverse Recovery Time		220		nS	VR=100V	
Qrr	Reverse Recovery Charge		2		μС	IS=7.3A di/dt=100A/μs	

Notes:

^{* 1.} Repetitive rating, pulse width limited by maximum junction temperature.

^{* 2.} Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 2%



Typical Feature Curve

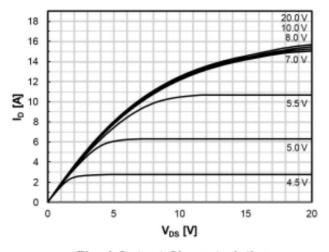


Fig. 1 Output Characteristics

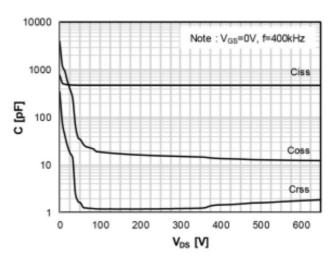


Fig. 2 Capacitances

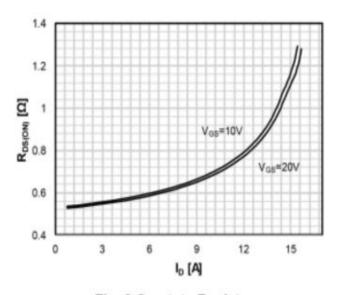


Fig. 3 On-state Resistance

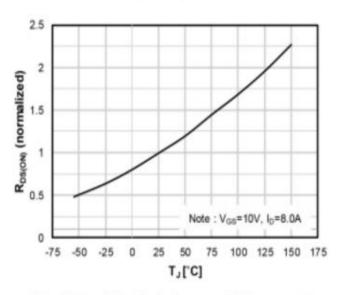


Fig. 4 On-state Resistance with Temperature

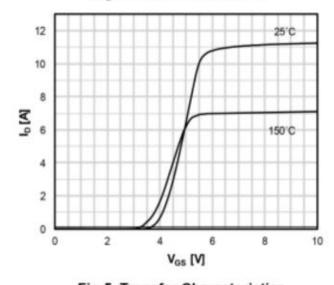


Fig 5. Transfer Characteristics

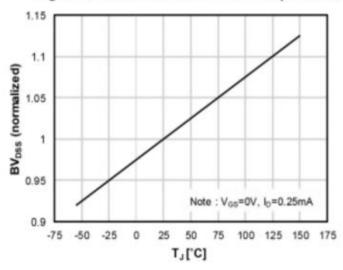
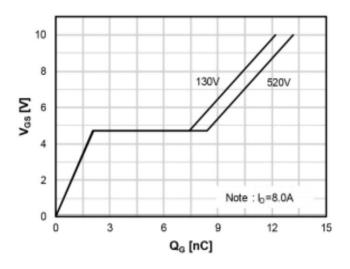


Fig 6. Breakdown Voltage with Temperature

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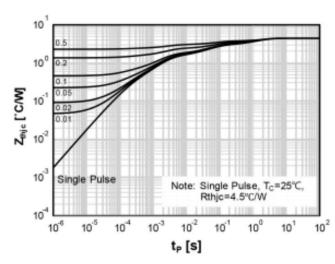




10 8 6 2 4 2 0 25 50 75 100 125 150 T_C ['C]

Fig 7. Gate Charge

Fig 8. Maximum Drain Current



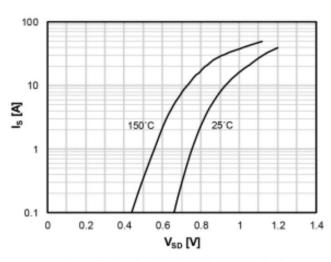
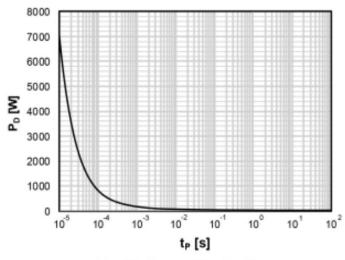


Fig 9. Maximum Transient Thermal Characteristics

Fig 10. Body Diode Characteristics



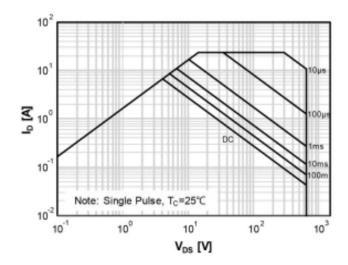


Fig 11. Power Dissipation

Fig 12. Safe Operating Area



Test Circuits and Waveforms

Figure A: Gate Charge Test Circuit and Waveform

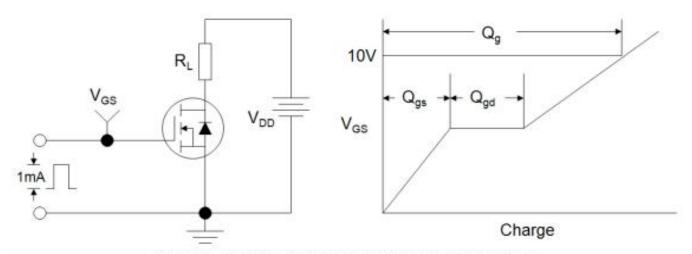


Figure B: Resistive Switching Test Circuit and Waveform

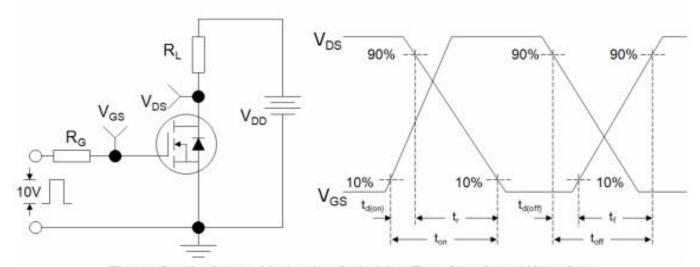
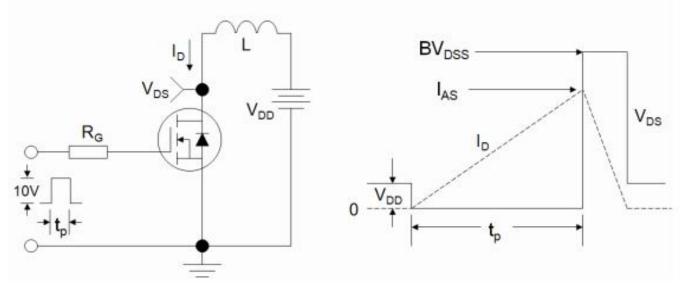


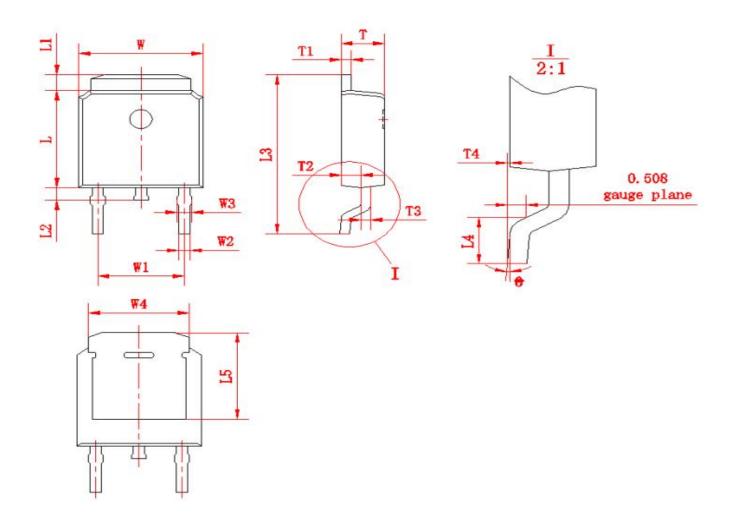
Figure C: Unclamped Inductive Switching Test Circuit and Waveform



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Package outline drawing(TO-252 Unit: mm)



符号	尺寸		符号	尺寸		 符号	尺寸	
14.2	Min	Max	1775	Min	Max	10 2	Min	Max
W	6.50	6.70	L1	0.80	1.20	T1	0.48	0.58
W1	(4.5	572)	L2	0.60 1.00		T2	0.95	1.15
W2	0.6	0.8	L3	9.70	10.30	ТЗ	0.48	0.58
W3	0.68	0.88	L4	1.30	1.70	T4	0.00	0.12
W4	(5.	.3)	L5	(5.20)		0	0	8
L	6.00	6.20	Т	2.20	2.40			



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